

AUF1405ZL-VB Datasheet

N-Channel 60 V (D-S) MOSFET

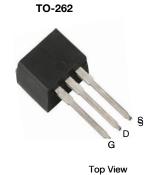
PRODUCT SUMMARY					
V _{DS} (V)	60				
$R_{DS(on)} (\Omega)$ at $V_{GS} = 10 V$	0.0028				
$R_{DS(on)}(\Omega)$ at $V_{GS} = 4.5 V$	0.0040				
I _D (A)	210				
Configuration	Single				

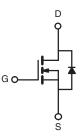
FEATURES

- Halogen-free According to IEC 61249-2-21
 Definition
- TrenchFET[®] Power MOSFET
- Package with Low Thermal Resistance
- 100 % R_g and UIS Tested
- Compliant to RoHS Directive 2002/95/EC



RoHS COMPLIANT HALOGEN FREE





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ($T_C = 25 \text{ °C}$, unless otherwise noted)						
PARAMETER		SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V _{DS}	60	V		
Gate-Source Voltage		V _{GS} ± 20		V		
Continuous Drain Current	T _C = 25 °C	1	210			
	T _C = 125 °C	I _D	120 ^a			
Continuous Source Current (Diode Conduction) ^a		I _S	120 ^a	А		
Pulsed Drain Current ^b		I _{DM}	480			
Single Pulse Avalanche Current		I _{AS}	75			
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	281	mJ		
Maximum Dawar Dissinctionh	T _C = 25 °C	D	375	W		
Maximum Power Dissipation ^b	T _C = 125 °C	P _D	125	vv		
Operating Junction and Storage Temperature Ra	ange	T _J , T _{stg}	- 55 to + 175	°C		

THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	LIMIT	UNIT		
Junction-to-Ambient	PCB Mount ^c	R _{thJA}	40	°C/W		
Junction-to-Case (Drain)		R _{thJC}	0.4	C/W		

Notes

- a. Package limited.
- b. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- c. When mounted on 1" square PCB (FR-4 material).

d. Parametric verification ongoing.

PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0, I_D = 250 \ \mu A$		60	-	-	V	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$		2.0	2.5		
Gate-Source Leakage	I _{GSS}	V _{DS} =	$V_{DS} = 0 V, V_{GS} = \pm 20 V$		-	± 100	nA	
		$V_{GS} = 0 V$	V _{DS} = 60 V	-	-	1.0		
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	$V_{DS} = 60 \text{ V}, \text{ T}_{J} = 125 ^{\circ}\text{C}$	-	-	50	μA	
		$V_{GS} = 0 V$	$V_{DS} = 60 \text{ V}, \text{ T}_{J} = 175 ^{\circ}\text{C}$	-	-	350		
On-State Drain Current ^a	I _{D(on)}	V _{GS} = 10 V	$V_{DS} \ge 5 V$	120	-	-	А	
		V _{GS} = 10 V	I _D = 30 A	-	0.0028	-	Ω	
Drain-Source On-State Resistance ^a	D D	V _{GS} = 10 V	I _D = 30 A, T _J = 125 °C	-	0.0060	-		
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$	I _D = 30 A, T _J = 175 °C	-	0.0080	-		
		$V_{GS} = 4.5 V$	I _D = 20 A	-	0.0040	-		
Forward Transconductanceb	9 _{fs}	V _{DS} = 15 V, I _D = 30 A		-	109	-	S	
Dynamic ^b								
Input Capacitance	C _{iss}		V V _{DS} = 25 V, f = 1 MHz	-	7300	9125	pF	
Output Capacitance	C _{oss}	$V_{GS} = 0 V$		-	935	1170		
Reverse Transfer Capacitance	C _{rss}			-	647	810		
Total Gate Charge ^c	Qg			-	184	276		
Gate-Source Charge ^c	Q _{gs}	V _{GS} = 10 V	$V_{DS} = 30 \text{ V}, \text{ I}_{D} = 110 \text{ A}$	-	24.7	-	nC	
Gate-Drain Charge ^c	Q _{gd}			-	50.4	-		
Gate Resistance	R _g	f = 1 MHz		0.5	1.1	1.6	Ω	
Turn-On Delay Time ^c	t _{d(on)}				19	29		
Rise Time ^c	t _r	$\label{eq:VDD} \begin{array}{l} V_{DD} = 30 \text{ V}, \ \textbf{R}_L = 0.27 \ \Omega \\ \textbf{I}_D \cong 110 \text{ A}, \ \textbf{V}_{GEN} = 10 \text{ V}, \ \textbf{R}_g = 2.5 \ \Omega \end{array}$		-	23	35	ns	
Turn-Off Delay Time ^c	t _{d(off)}			-	83	125		
Fall Time ^c	t _f			-	35	53		
Source-Drain Diode Ratings and Char	acteristics ^b	·			•			
Pulsed Current ^a	I _{SM}			-	-	480	А	
Forward Voltage	V _{SD}	I _F = 100 A, V _{GS} = 0			0.9	1.5	V	

Notes

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

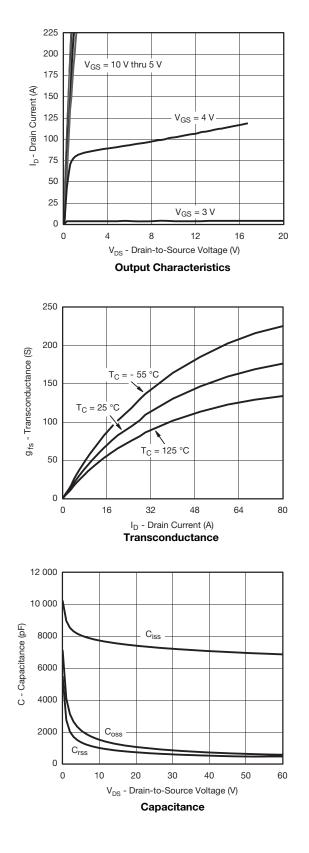
c. Independent of operating temperature.

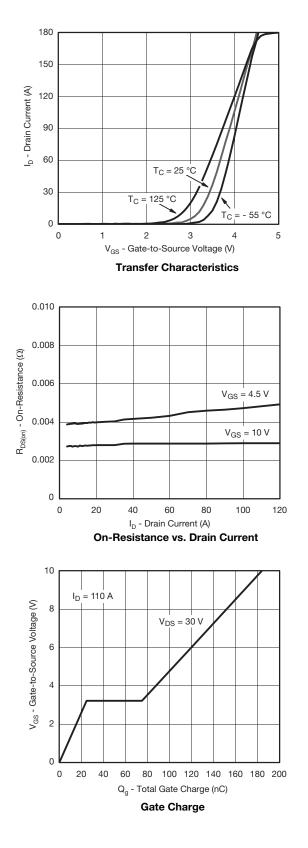
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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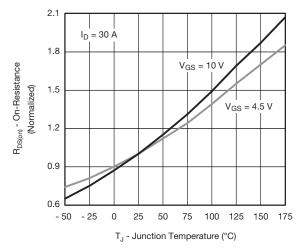
TYPICAL CHARACTERISTICS ($T_A = 25$ °C, unless otherwise noted)



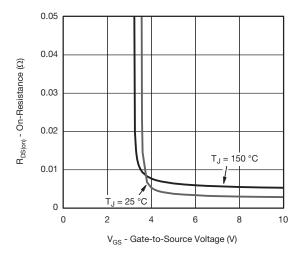




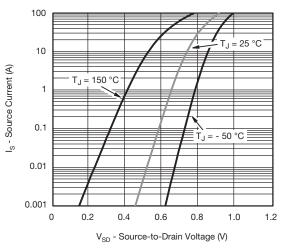
TYPICAL CHARACTERISTICS ($T_A = 25 \text{ °C}$, unless otherwise noted)



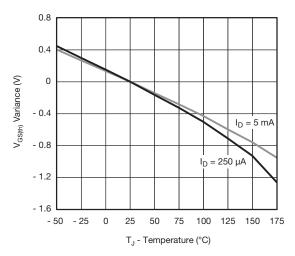




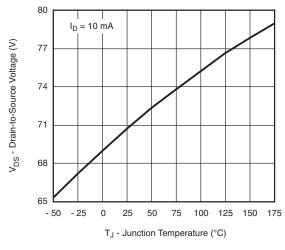
On-Resistance vs. Gate-to-Source Voltage



Source Drain Diode Forward Voltage



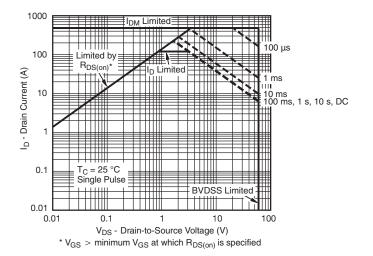




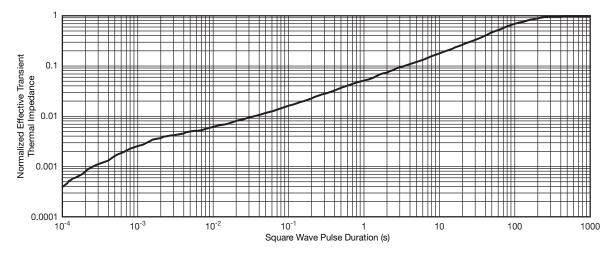
Drain Source Breakdown vs. Junction Temperature



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



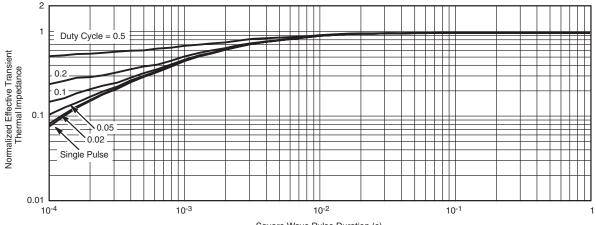
Safe Operating Area



Normalized Thermal Transient Impedance, Junction-to-Ambient



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



Square Wave Pulse Duration (s)

Normalized Thermal Transient Impedance, Junction-to-Case

Note

• The characteristics shown in the two graphs

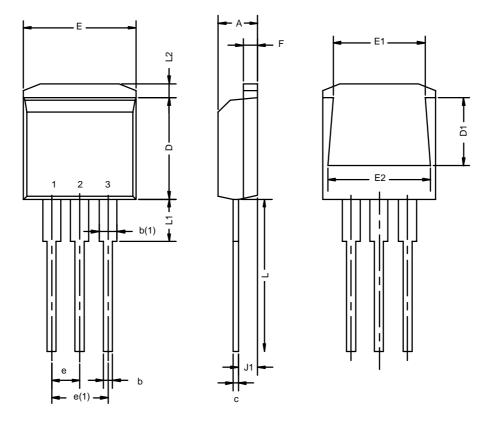
- Normalized Transient Thermal Impedance Junction-to-Ambient (25 °C)

- Normalized Transient Thermal Impedance Junction-to-Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.



TO-262: 3-LEAD



	MILLIM	ETERS*	INCHES		
Dim	Min	Max	Min	Max	
Α	4.32	4.70	0.170	0.185	
b	0.64	1.00	0.025	0.039	
b(1)	1.14	1.40	0.045	0.055	
С	0.36	0.50	0.014	0.020	
D	8.64	9.65	0.340	0.380	
D1	5.59	6.10	0.220	0.240	
е	2.41	2.67	0.095	0.105	
e(1)	4.95	5.33	0.195	0.210	
E	10.03	10.41	0.395	0.410	
E1	7.87	8.64	0.310	0.340	
E2	9.02	9.53	0.355	0.375	
F	1.14	1.40	0.045	0.055	
J1	2.41	2.79	0.095	0.110	
L	13.08	14.22	0.515	0.560	
L1	-	3.81	-	0.150	
L2	1.02	1.40	0.040	0.055	
ECN: T-02234—Rev. C, 14-Oct-02 DWG: 5855					

*Use millimeters as the primary measurement



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